			图	, E			SHEET	1 OF	1	
INFORMATION DISCLOSURE CITATION IN AN				ATTY. DOCKET NO. SERIAL NO. 10/083,694						
APPLICATION										
AITLICATION				APPLICANT Bruce W. SMITH						
(PTO-1449)				FILING DATE GROUP February 27, 2002 2851						
	700			USCPATIEN	EDOGÚMENTS					
EXAMINER'S INITIALS	CITE NO.	Document Number Number-Kind Codez (# 1000m)		Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document		Pages, Columns, Unes, Where Relevant Passages or Relevant Figures Appear			
PK		US	5,229,230	07/20/1993	Kamon					
2/2		US	5,821,014	10/13/1998	Chen et al.					
211		US	6,048,647	04/11/2000	Miyazaki et al.					
		US								
		US								
		US								
		US								
		US								
		US								
		US								
		US								
		US								
		us				() in the same place.	erengen en	er Krist		
		,		Publication Date	FENTIDOCUMENTS Name of Patentee or Applicant of C		Pages, Columns,		slation	
EXAMINER'S INITIALS	CITE NO.	Foreign Patent Document Country Codes -Number 4-Kind Codes (if known)		MM-DD-YYYY	Document .		Lines Where Relevant Figures Appear		Yes No	
07.	A2	 	EP 1 174 764	01/23/2002	ASM LITHOGRAPHY B.V. and					
1000	UL 2 EF 11/4/04 01/23			ASML MASKTOOLS NETHERLAND				<u> </u>		
Ch	A1	EP 1 152 288		11/07/2001	ASML MASKTOOLS NETHERLAND					
26		JP 11143047 English abstract)		05/28/1999	NEC Corp.					
04			JP 08186073 English abstract	07/16/1996	MITSUBISHI ELECTRIC CORP.	-, - ,				
2/			JP 07064274 English abstract	03/10/1995	3011 0014 .					
TEST STATE	247142	A.S	A THE PARTICIPATION OF THE PARTY	RAILLEUDINGIAUT	of Title Date (Redinent Pages: Etc.)		Control of the state of the sta	12134	e Mai	
EXAMINER'S INITIALS	CITE NO.	Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city and/or country where published.								
2/1	11C-2-32L	"NAKAO S ET AL", "A Novel RET for Random Pattern Formation Utilizing Attenuating Non 44, 45, 2000, Tokyo, Japan XP010513500					Shift Assist Pattem*, pp			
 		\vdash						+-		
	 	╁								
	7./	E	KAMINER / /	T	DAJE (CONSIDE	RED			

*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

1 Applicant's unique citation designation number (optional). 2 Applicant is to place a check mark here if English language Translation is attached.

SHEET	1	OF	•
		OI.	

								SHEET	<u> </u>	<u>. T</u>	
INFORMATION DISCLOSURE					- 1.	ATTY. DOCKET NO.	SERI	AL NO:			
					. !	55071-129	10/083,694				
CITATION IN AN APPLICATION (PTO-1449)							- 5,5	,			
PAEN	\ A1	ppr	LICATION	1 - 7							
	ري (الخ				∀ `⊢						
# .~~	المِين ا		(), ,	MV	4	APPLICANT					
17 200	3 원		(//	7	(Bruce W. SMITH					
10r .	Ş ,	/D/I	20.1440)	'		FILING DATE GROUP					
(PTO-1449)					- 17	February 27, 2002	2851				
							2031				
				U.S. PATE	NT D	OCUMENTS					
EXAMINER'S	1	\vdash	Document Number	Publication Da	ate	Name of Patentee or Applicant of Ci	ited	Pages, Columns, Li	nes Wi	nerre	
INITIALS	CITE NO.	Num	er-Kind Codez (# known)	MM-DD-YYY		Document		Relevant Passages	or Rele		
				İ			- 1	Figures Appear			
l		US	5,229,230	07/20/1993		Kamon		7.7° , 1° 10° , 7° , 10°			
}- 		US	5,821,014	10/13/1998		Chen et al.					
	 	US	6,948,647	04/11/2000		Miyazaki et al.					
		US	2,7,3,0,1	5	-+	. Wilyazani et al.		Vice filtre			
		us	 		-	•					
		US			+		\dashv				
		US	. \		\dashv						
	ļ	US		-		•	 -				
		US				· · · · · · · · · · · · · · · · · · ·					
		US			+						
		US	•		- -		-		-		
		US			-+		-				
	·	US					-+				
	-	US		\	-		- 				
	I	l		FOREIGNP	PATENT	DOCUMENTS					
EXAMINER'S		Fo	reign Patent Document	Publication Dat	<u> </u>	Name of Patentee or Applicant of Cited Pages, Columns,				slation	
INITIALS	CITE NO.	Country Codes -Number 4 -Kind		MM-OD-YYYY	<i>r</i>	Document		Lines Where			
		Codes (if known)						Relevant Figures Appear			
								∼phea:	Yes	No	
	A2		EP 1 174 764	. 01/23/2002		ASM LITHOGRAPHY B.V. and			163	140	
	, ' ' '				l A	ASML MASKTOOLS NETHERLANDS					
	A1	EP 1 152 288		11/07/2001		ASML MASK TOOLS NETHERLANDS		J. 72 JAN.	\vdash	_	
		JP 11143047 English		05/28/1999		NEC Corp.			\vdash		
			abstract)								
		,	JP 08186073 English abstract	07/16/1996		MITSUBISHI ELECTRIC CORP.					
		<u> </u>	JP 07064274 English	03/10/1995		SONY CORP.			 		
		١,	abstract	03/10/1885		SUNT CORP.					
			OTHER A	RT (Including Aut	thor, Titl	le, Date, Pertinent Pages, Etc.)	لــــــــــــــــــــــــــــــــــــــ		لـــيـا		
EXAMINER'S		Inclu	de name of the author (in (CAPITAL LETTE	RS), title	e of the article (when appropriate), titl	e of the	item (book, magazine.			
INITIALS	CITE NO.	journ	al, serial, symposium, cata	alog, etc.), date, p	page(s),	, valume-issue number(s), publisher,	city and/	or country where			
		publi	shed.								
	11C-2-32L	"NA	KAO S ET AL", "A Novel F	RET for Random	Pattern	Formation Utilizing Attenuating Non-	Phase-S	hift Assist Pattern" no	_		
		"NAKAO S ET AL", "A Novel RET for Random Pattern Formation Utilizing Attenuating Non-Phase-Shift Assist Pattern", pp. 44, 45, 2000, Tokyo, Japan XP010513500									
		\							\neg		
EXAMINER					DATE CO	DNSIDE	RED				
					1			\			

^{*}EXAMINER: Initial if reference considered, whether or not ditation is in conformance with MPEP 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

1 Applicant's unique citation designation number (optional). 2 Applicant is to place a check mark here if English language Translation is attached.